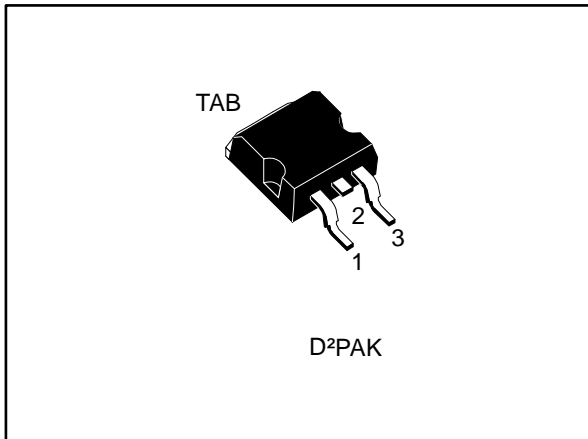
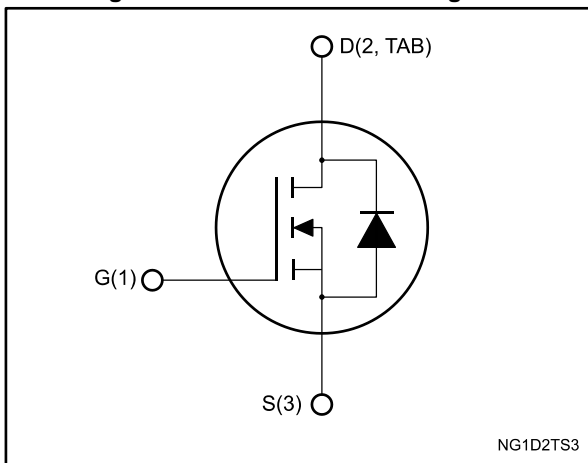


N-channel 100 V, 3.4 mΩ typ., 110 A, STripFET™ F7 Power MOSFET in a D²PAK package

Datasheet - custom data


Figure 1: Internal schematic diagram

Table 1: Device summary

Order code	Marking	Package	Packaging
STB15810	15810	D ² PAK	Tape and reel

Features

Order code	V _{DS}	R _{DS(on)max}	I _D	P _{TOT}
STB15810	100 V	3.9 mΩ	110 A	250 W

- 100% avalanche tested
- Ultra low on-resistance

Applications

- Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Contents

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2	Electrical characteristics	4
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3	Test circuits	8
4	Package information	9
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5	Revision history	13

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	100	V
V _{GS}	Gate- source voltage	±20	V
I _D	Drain current (continuous) at T _C = 25 °C	110	A
I _D	Drain current (continuous) at T _C = 100 °C	110	A
I _{DM} ⁽¹⁾	Drain current (pulsed) T _C = 25 °C	440	A
P _{TOT}	Total dissipation at T _C = 25 °C	250	W
E _{AS} ⁽²⁾	Single pulse avalanche energy	495	mJ
T _J	Operating junction temperature range	-55 to 175	°C
T _{stg}	Storage temperature range		

Notes:

⁽¹⁾Pulse width is limited by safe operating area.

⁽²⁾Starting T_J = 25 °C, I_D = 30 A, V_{DD} = 50 V

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	0.6	°C/W
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb	35	°C/W

Notes:

⁽¹⁾When mounted on 1 inch² FR-4 board, 2 oz Cu

2 Electrical characteristics

($T_C = 25\text{ }^\circ\text{C}$ unless otherwise specified)

Table 4: On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	100			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 100\text{ V}$			1	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 100\text{ V}$, $T_C = 125\text{ }^\circ\text{C}$ ⁽¹⁾			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = 20\text{ V}$			100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	2.5		4.5	V
$R_{DS(on)}$	Static drain-source on- resistance	$V_{GS} = 10\text{ V}$, $I_D = 55\text{ A}$		3.4	3.9	m Ω

Notes:

⁽¹⁾Defined by design, not subject to production test.

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 50\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	8115	-	pF
C_{oss}	Output capacitance		-	1510	-	pF
C_{riss}	Reverse transfer capacitance		-	67	-	pF
Q_g	Total gate charge	$V_{DD} = 50\text{ V}$, $I_D = 110\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 14: "Test circuit for gate charge behavior")	-	117	-	nC
Q_{gs}	Gate-source charge		-	47	-	nC
Q_{gd}	Gate-drain charge		-	26	-	nC

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 50\text{ V}$, $I_D = 55\text{ A}$, $R_G = 4.7\ \Omega$, $V_{GS} = 10\text{ V}$ (see Figure 13: "Test circuit for resistive load switching times" and Figure 18: "Switching time waveform")	-	33	-	ns
t_r	Rise time		-	57	-	ns
$t_{d(off)}$	Turn-off delay time		-	72	-	ns
t_f	Fall time		-	33	-	ns

Table 7: Source drain diode

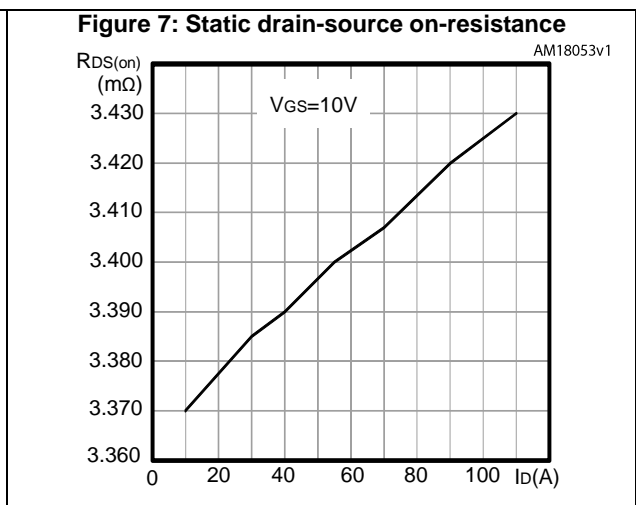
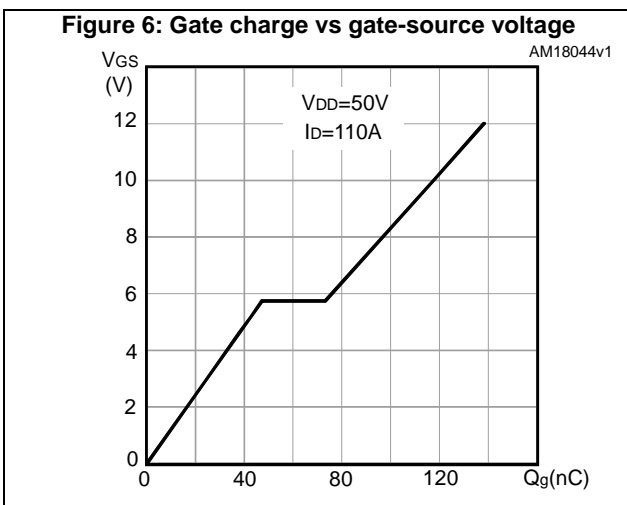
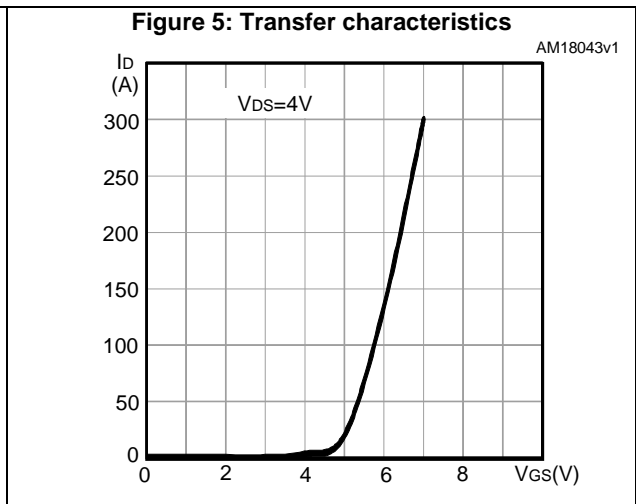
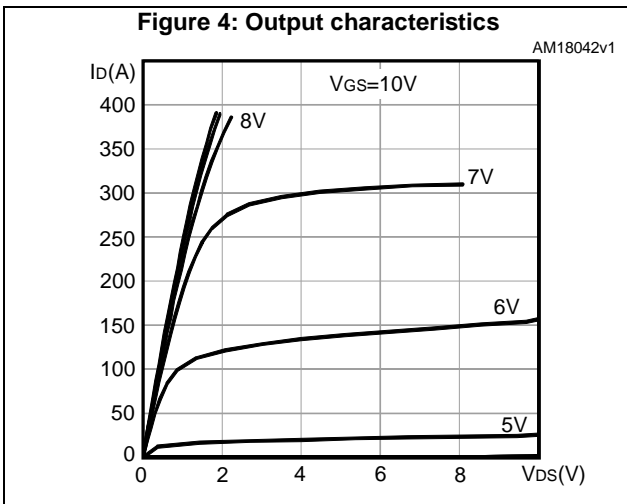
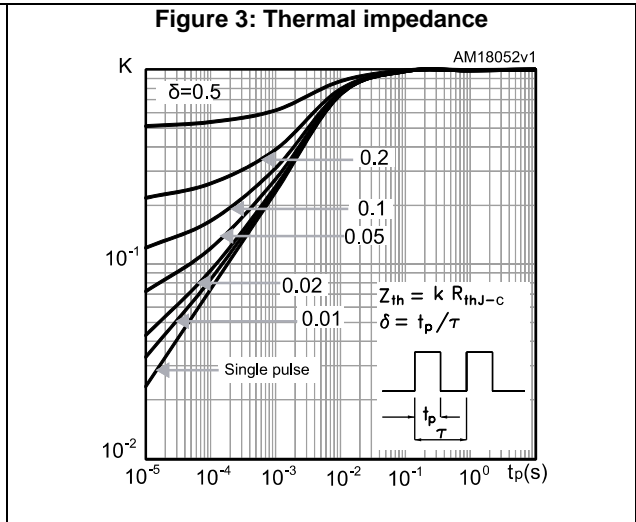
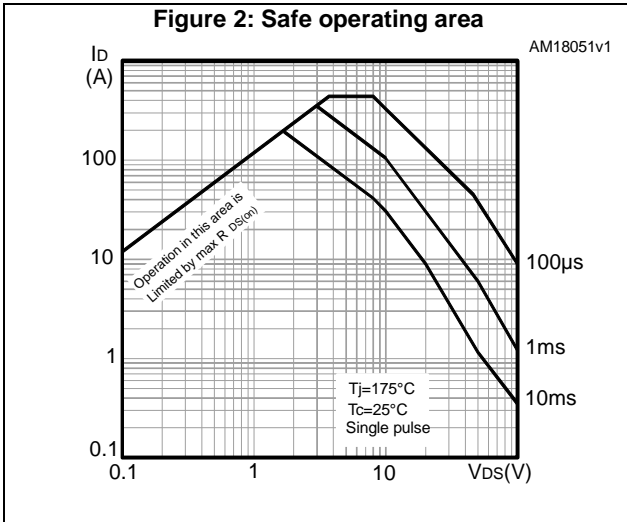
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		110	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		440	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 110\text{ A}$, $V_{GS} = 0$	-		1.2	V
t_{rr}	Reverse recovery time	$I_{SD} = 110\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 80\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ (see Figure 15: "Test circuit for inductive load switching and diode recovery times")	-	70		ns
Q_{rr}	Reverse recovery charge		-	165		nC
I_{RRM}	Reverse recovery current		-	4.7		A

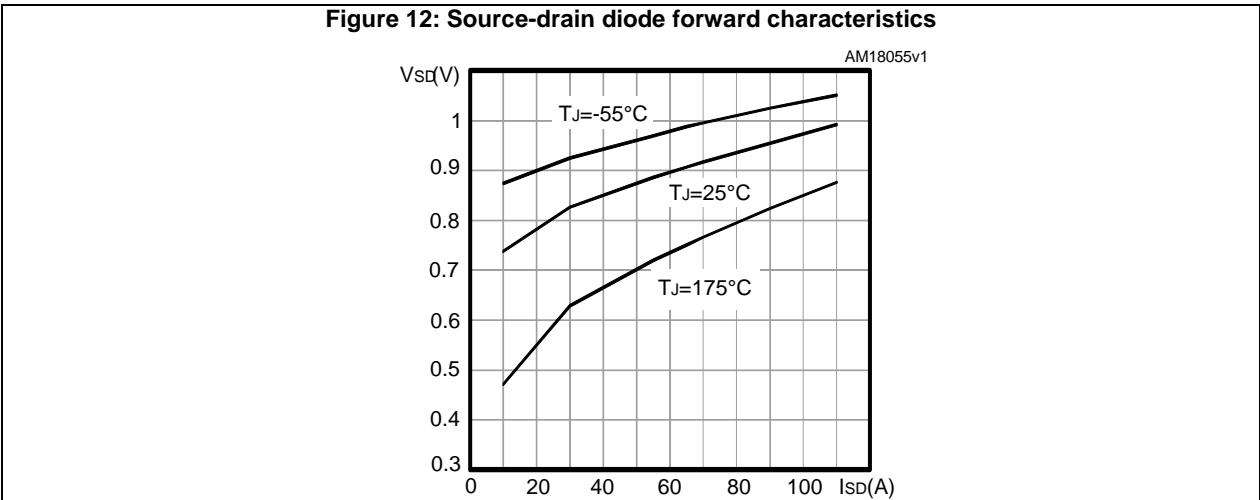
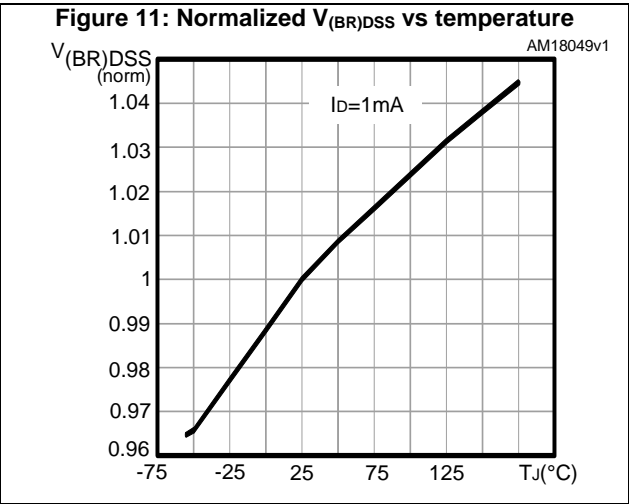
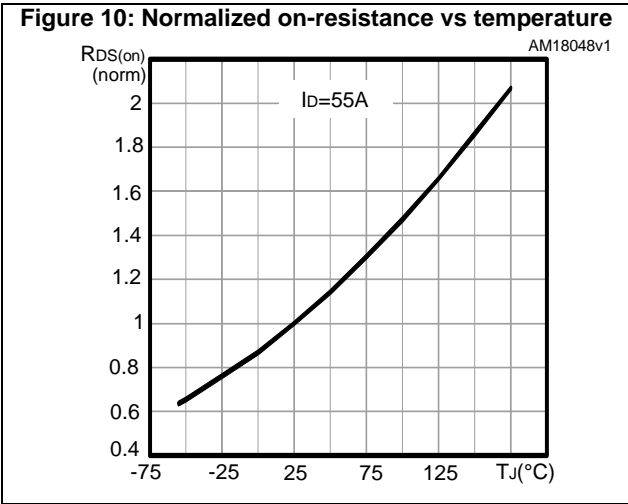
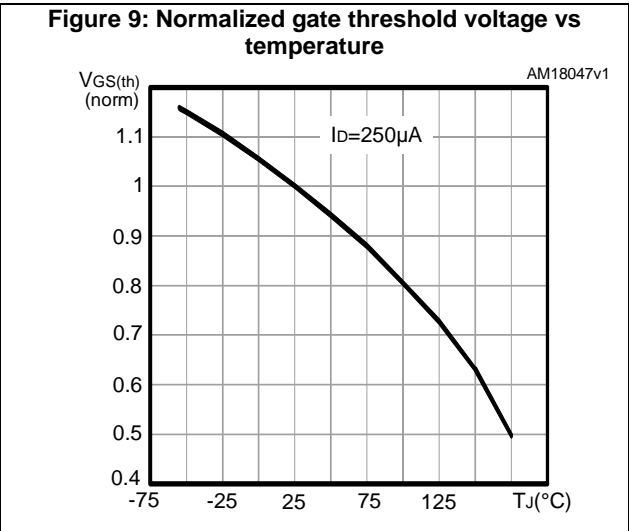
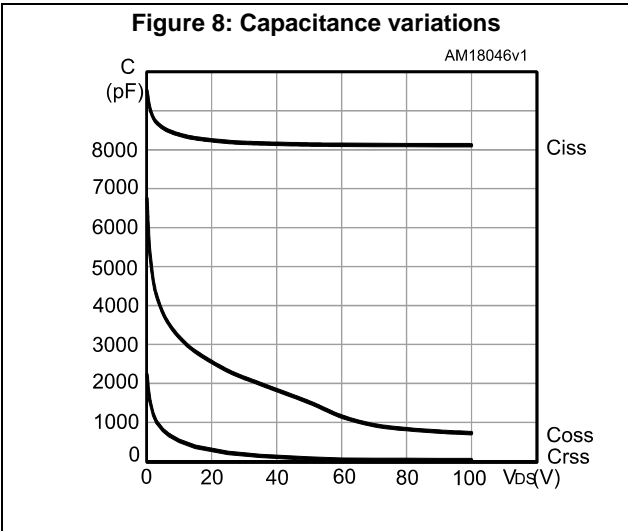
Notes:

(1)Pulse width is limited by safe operating area.

(2)Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)





3 Test circuits

Figure 13: Test circuit for resistive load switching times



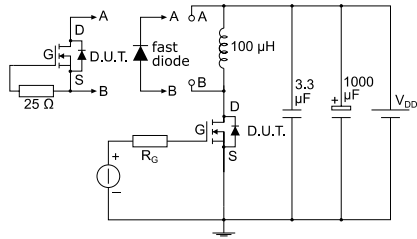
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Figure 14: Test circuit for gate charge behavior



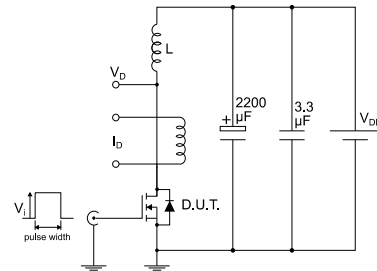
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Figure 15: Test circuit for inductive load switching and diode recovery times



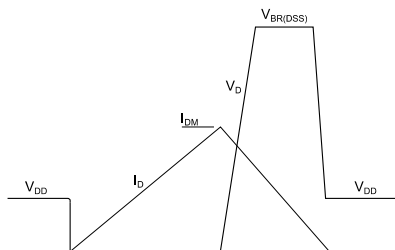
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Figure 16: Unclamped inductive load test circuit



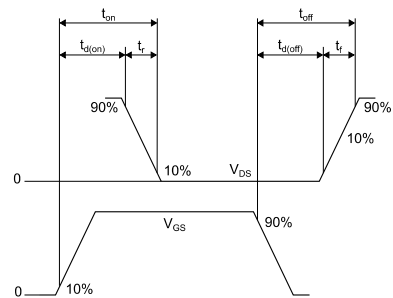
AM01471v1

Figure 17: Unclamped inductive waveform



AM01472v1

Figure 18: Switching time waveform



AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 D²PAK (TO-263) type B package information

Figure 19: D²PAK (TO-263) type B package outline

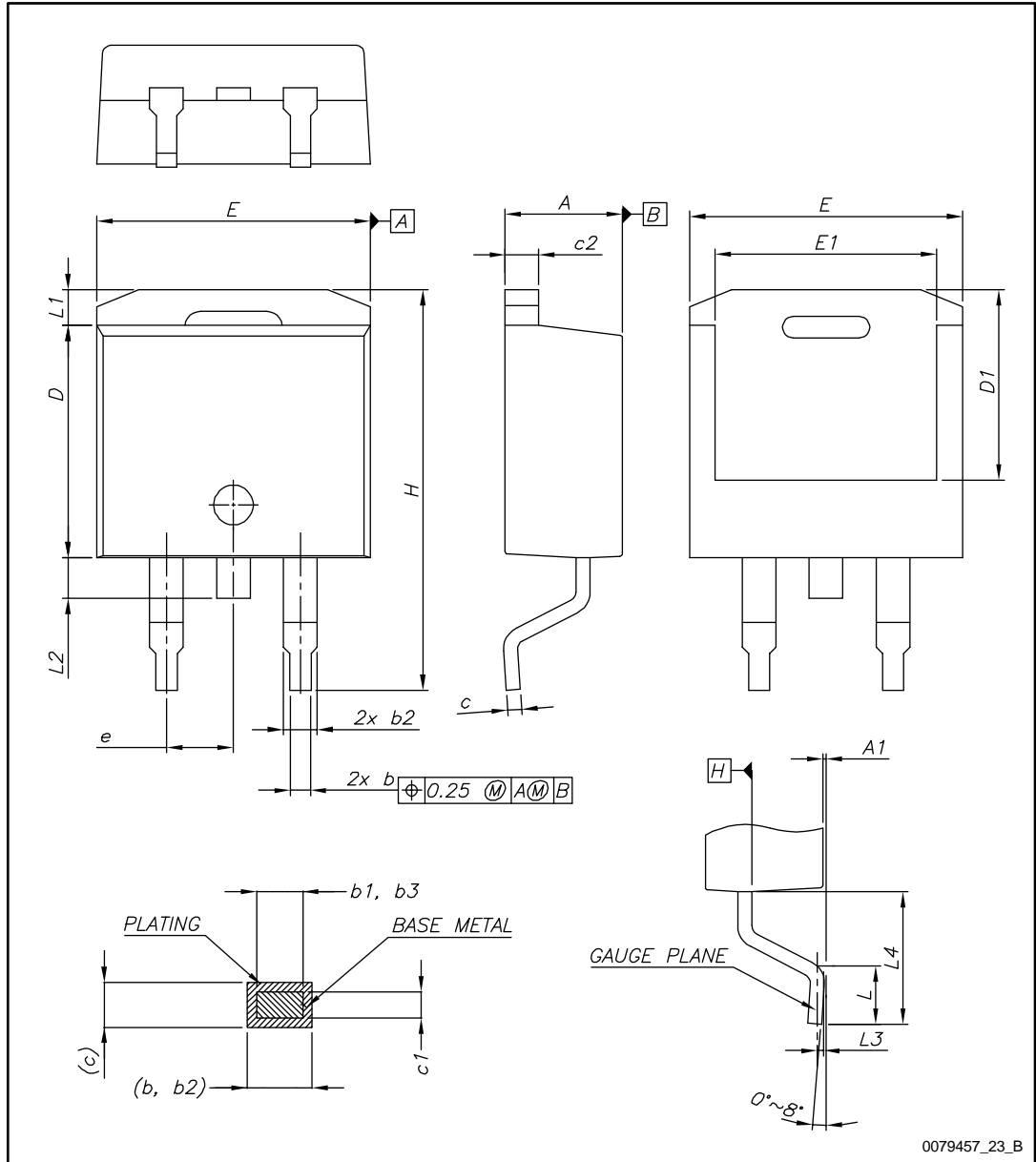
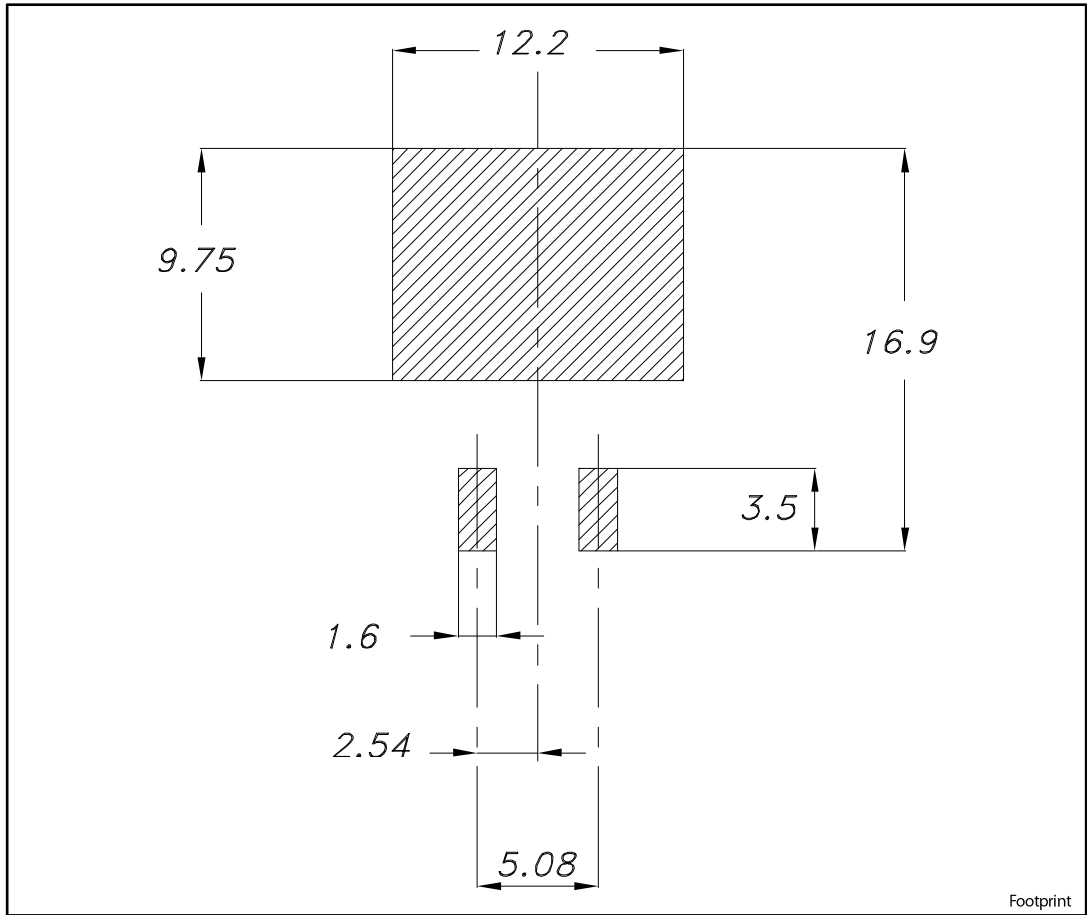


Table 8: D²PAK (TO-263) type B mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.36		4.56
A1	0		0.25
b	0.70		0.90
b1	0.51		0.89
b2	1.17		1.37
b3	1.36		1.46
c	0.38		0.694
c1	0.38		0.534
c2	1.19		1.34
D	8.60		9.00
D1	6.90		7.50
E	10.15		10.55
E1	8.10		8.70
e	2.54 BSC		
H	15.00		15.60
L	1.90		2.50
L1			1.65
L2			1.78
L3		0.25	
L4	4.78		5.28

Figure 20: D²PAK (TO-263) type B recommended footprint (dimensions are in mm)



4.2 D²PAK type B packing information

Figure 21: D2PAK type B tape outline

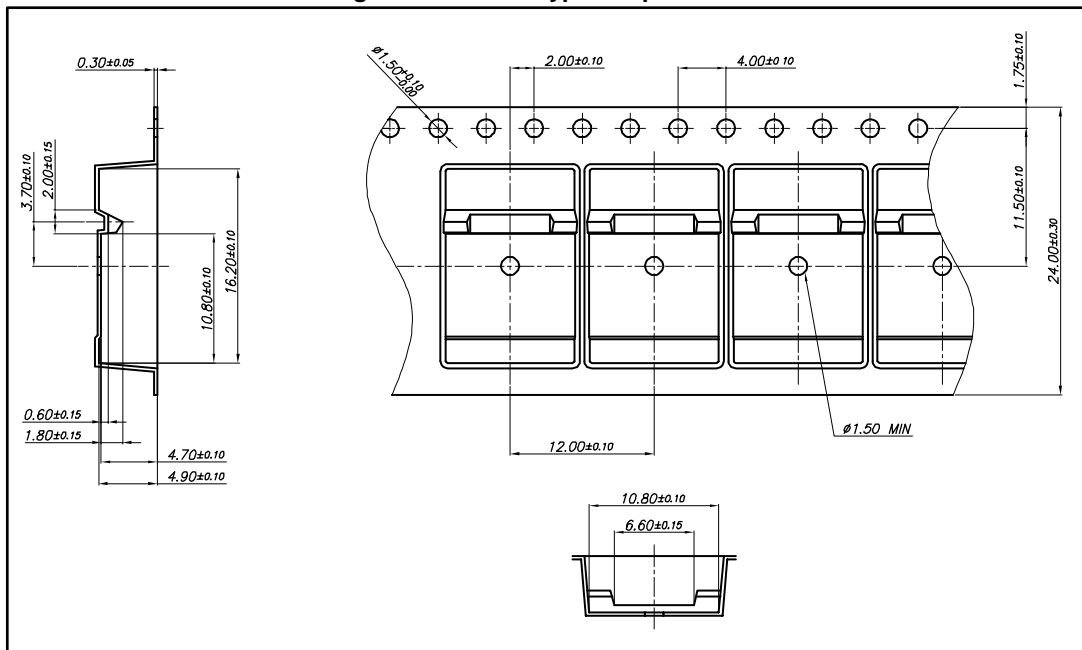
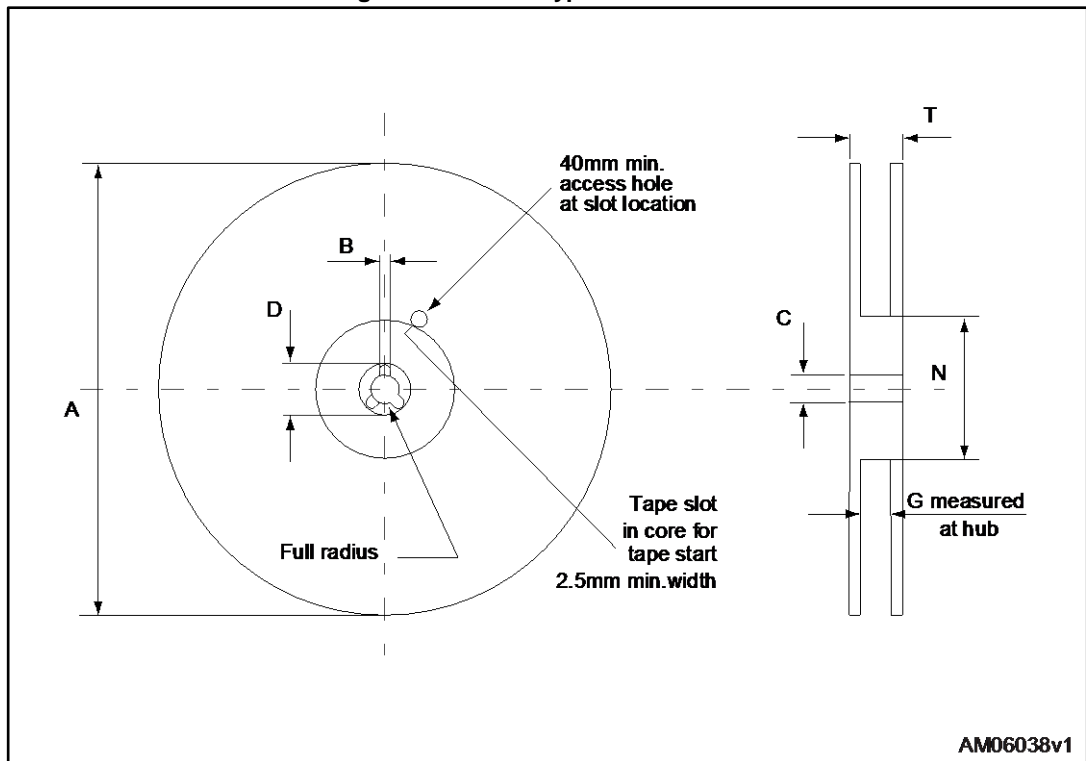


Figure 22: D2PAK type B reel outline



AM06038v1

Table 9: D²PAK type B reel mechanical data

Dim.	mm	
	Min.	Max.
A		330
B	1.5	
C	12.8	13.2
D	20.2	
G	24.4	26.4
N	100	
T		30.4

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
07-Mar-2017	1	First release

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